## **ON Semiconductor**



# Final Product/Process Change Notification Document # : FPCN21371X

Issue Date: 22 June 2016

Title of Change:	Qualification of Advanced Semiconductor Engineering (ASE), located in Shanghai, China for assembly of devices AMIS49587C5872G and AMIS49587C5872RG.			
Proposed first ship date:	29 September 2016 or earlier after customer approval			
Contact information:	Contact your local ON Semiconductor Sales Office or <thelma.hammer@onsemi.com></thelma.hammer@onsemi.com>			
Samples:	Contact your local ON Semiconductor Sales Office or <john.wollen@onsemi.com></john.wollen@onsemi.com>			
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or <andy.esteva@onsemi.com></andy.esteva@onsemi.com>			
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change.         ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <pcn.support@onsemi.com>.</pcn.support@onsemi.com>			
Change Part Identification:	Affected products will be identified with assembly site code in the marking along with the date code.			
Change category:	Uwafer Fab Change Assembly Change Test Change Other			
Change Sub-Category(s):	Droduct crocific change	<ul> <li>Datasheet/Product Doc change</li> <li>Shipping/Packaging/Marking</li> <li>Other:</li> </ul>		
Sites Affected:	oplicable ON Semiconductor site(s) :	External Foundry/Subcon site(s) Advanced Semiconductor Engineering Shanghai		
Description and Purpose:				

This is a Final Change Notification to announce that Advanced Semiconductor Engineering (ASE) located in Shanghai, China has been successfully qualified as an assembly source for the affected devices below. There is no impact on the electrical performance of the affected devices. This will allow additional manufacturing capacity and flexibility. Upon the expiration of this FPCN, assembly of the affected devices will be produced in either of the two locations, ASE Shanghai or Unisem, Batam.



### **Reliability Data Summary:**

QV Device Name: 20241-010-XTD

Report ID: NQFP\_AS\_A01

Package: QFN 52 8X8

Test	Specification	Condition	Interval	Results
HTOL	JESD22-A108	Ta=125°C, 100 % max rated Vcc	1000 hrs	0/240
HTSL	JESD22-A103	Ta= 125°C	1008 hrs	0/77
тс	JESD22-A104	Ta= -65°C to +150°C	500 сус	0/231
HAST	JESD22-A110	110°C, 85% RH, 18.8psig, bias	264 hrs	0/231
uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/231
РС	J-STD-020 JESD-A113	MSL 3 @ 260 °C		
SD	JSTD002	Ta = 245C, 10 sec		0/ 45

### **Electrical Characteristic Summary:**

Electrical characteristics are not impacted.

### List of Affected Standard Parts:

Part Number	Qualification Vehicle	
AMIS49587C5872G	20241-010-XTD	
AMIS49587C5872RG	20241-010-XTD	